

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination AWAI ET AL.	
		Examiner Cheukfan Lee	Art Unit 2625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,151,622	12-2006	Suzuki et al.	358/498
*	B	US-4,969,048	11-1990	Hoshino, Seiji	358/296
*	C	US-6,178,017	01-2001	Ishida, Yasushi	358/498
*	D	US-5,884,117	03-1999	Tanoue et al.	399/1
*	E	US-6,115,564	09-2000	Morimoto, Yasumasa	399/92
*	F	US-5,552,902	09-1996	Kohno, Takeshi	358/498
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.